Power MOSFET

30 V, 66 A, Single N-Channel, SO-8FL

Features

- Low R_{DS(ON)} to Minimize Conduction Losses
- Low Capacitance to Minimize Driver Losses
- Optimized Gate Charge to Minimize Switching Losses
- These are Pb–Free Devices

Applications

- CPU Power Delivery
- DC-DC Converters

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MAXIMUM RATINGS (T_J = 25°C unless otherwise stated)

Parameter			Symbol	Value	Unit
Drain-to-Source Voltage			V_{DSS}	30	V
Gate-to-Source Vol	Gate-to-Source Voltage			±20	V
Continuous Drain		T _A = 25°C	I _D	15	Α
Current R _{θJA} (Note 1)		T _A = 85°C		11	
Power Dissipation R _{0JA} (Note 1)		T _A = 25°C	P _D	2.17	W
Continuous Drain			ID	9.5	Α
Current R _{θJA} (Note 2)	Steady	T _A = 85°C		7.0	
Power Dissipation R _{0JA} (Note 2)	State	T _A = 25°C	P _D	0.87	W
Continuous Drain	1	T _C = 25°C	I _D	66	Α
Current R _{θJC} (Note 1)		T _C = 85°C		48	
Power Dissipation R ₀ JC (Note 1)		T _C = 25°C	P _D	41.7	W
Pulsed Drain Current	$T_A = 25^{\circ}C,$ $t_p = 10 \ \mu s$		I _{DM}	132	Α
Operating Junction and Storage Temperature			T _J , T _{STG}	–55 to +150	°C
Source Current (Body Diode)			I _S	35	Α
Drain to Source DV/DT			dV/dt	6	V/ns
Energy $T_J = 25^{\circ}C$, V	Single Pulse Drain–to–Source Avalanche Energy T_J = 25°C, V_{DD} = 30 V, V_{GS} = 10 V, I_L = 19 A_{pk} , L = 1.0 mH, R_G = 25 Ω			180.5	mJ
Lead Temperature for Soldering Purposes (1/8" from case for 10 s)			TL	260	°C

Stresses exceeding Maximum Ratings may damage the device. Maximum Ratings are stress ratings only. Functional operation above the Recommended Operating Conditions is not implied. Extended exposure to stresses above the Recommended Operating Conditions may affect device reliability.

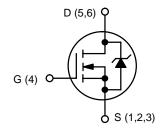
- 1. Surface-mounted on FR4 board using 1 sq-in pad, 1 oz Cu.
- 2. Surface—mounted on FR4 board using the minimum recommended pad size. *For additional information on our Pb—Free strategy and soldering details, please download the ON Semiconductor Soldering and Mounting Techniques Reference Manual, SOLDERRM/D.



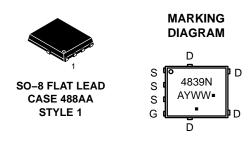
ON Semiconductor®

http://onsemi.com

V _{(BR)DSS}	V _{(BR)DSS} R _{DS(ON)} MAX	
30 V	5.5 mΩ @ 10 V	CC A
30 V	9.5 mΩ @ 4.5 V	66 A



N-CHANNEL MOSFET



A = Assembly Location

Y = Year WW = Work Week = Pb-Free Package

(Note: Microdot may be in either location)

ORDERING INFORMATION

Device	Package	Shipping [†]
NTMFS4839NT1G	SO-8FL (Pb-Free)	1500 / Tape & Reel
NTMFS4839NT3G	SO-8FL (Pb-Free)	5000 / Tape & Reel

†For information on tape and reel specifications, including part orientation and tape sizes, please refer to our Tape and Reel Packaging Specifications Brochure, BRD8011/D.

THERMAL RESISTANCE MAXIMUM RATINGS

Parameter	Symbol	Value	Unit
Junction-to-Case (Drain)	$R_{ heta JC}$	3.0	
Junction-to-Ambient - Steady State (Note 3)	$R_{ heta JA}$	57.7	°C/W
Junction-to-Ambient - Steady State (Note)	$R_{\theta JA}$	143.4	

- Surface–mounted on FR4 board using 1 sq-in pad, 1 oz Cu.
 Surface–mounted on FR4 board using the minimum recommended pad size.

ELECTRICAL CHARACTERISTICS ($T_J = 25$ °C unless otherwise specified)

Parameter	Symbol	Test Condition		Min	Тур	Max	Unit
OFF CHARACTERISTICS							
Drain-to-Source Breakdown Voltage	V _{(BR)DSS}	$V_{GS} = 0 \text{ V}, I_D = 250 \mu\text{A}$		30			V
Drain-to-Source Breakdown Voltage Temperature Coefficient	V _{(BR)DSS} /				25		mV/°C
Zero Gate Voltage Drain Current	I _{DSS}	V _{GS} = 0 V, V _{DS} = 24 V	T _J = 25 °C			1	μΑ
			T _J = 125°C			10	
Gate-to-Source Leakage Current	I _{GSS}	$V_{DS} = 0 \text{ V}, V_{GS}$	= ±20 V			±100	nA
ON CHARACTERISTICS (Note 5)							
Gate Threshold Voltage	V _{GS(TH)}	$V_{GS} = V_{DS}, I_D =$	= 250 μΑ	1.5		2.5	V
Negative Threshold Temperature Coefficient	V _{GS(TH)} /T _J				5.8		mV/°
Drain-to-Source On Resistance	R _{DS(on)}	$V_{GS} = 10 \text{ V to}$	I _D = 30 A		4.5	5.5	
		11.5 V	I _D = 15 A		4.5		
		V _{GS} = 4.5 V	I _D = 30 A		8.4	9.5	mΩ
			I _D = 15 A		8.4		
Forward Transconductance	9FS	V _{DS} = 15 V, I _D = 15 A			14.7		S
CHARGES, CAPACITANCES & GATE RESIS	STANCE			•		•	•
Input Capacitance	C _{ISS}	V _{GS} = 0 V, f = 1 MHz, V _{DS} = 12 V			1588		pF
Output Capacitance	C _{OSS}				352		
Reverse Transfer Capacitance	C _{RSS}				196		
Total Gate Charge	Q _{G(TOT)}	$V_{GS} = 4.5 \text{ V}, V_{DS} = 15 \text{ V}; I_D = 30 \text{ A}$			13	18	nC
Threshold Gate Charge	Q _{G(TH)}				1.6		
Gate-to-Source Charge	Q_{GS}				4.8		
Gate-to-Drain Charge	Q_{GD}				5.8		
Total Gate Charge	Q _{G(TOT)}	V _{GS} = 11.5 V, V _{DS} = 15 V; I _D = 30 A			28		nC
SWITCHING CHARACTERISTICS (Note 6)							
Turn-On Delay Time	t _{d(ON)}				12		
Rise Time	t _r	$V_{GS} = 4.5 \text{ V}, V_{DS} = 15 \text{ V}, I_{D} = 15 \text{ A},$ $R_{G} = 3.0 \Omega$			29		ns
Turn-Off Delay Time	t _{d(OFF)}				18		
Fall Time	t _f				7.0		
Turn-On Delay Time	t _{d(ON)}	$V_{GS} = 11.5 \text{ V}, V_{DS} = 15 \text{ V},$ $I_{D} = 15 \text{ A}, R_{G} = 3.0 \Omega$			8.0		ns
Rise Time	t _r				21		
Turn-Off Delay Time	t _{d(OFF)}				24		
Fall Time	t _f				7.0		

- 5. Pulse Test: pulse width $\leq 300~\mu s$, duty cycle $\leq 2\%$.
 6. Switching characteristics are independent of operating junction temperatures.

ELECTRICAL CHARACTERISTICS (T_{.1} = 25°C unless otherwise specified)

Parameter	Symbol	Test Condition		Min	Тур	Max	Unit
DRAIN-SOURCE DIODE CHARACTERISTICS							
Forward Diode Voltage	V _{SD}	V _{GS} = 0 V,	T _J = 25°C		0.9	1.2	
		$V_{GS} = 0 \text{ V},$ $I_{S} = 30 \text{ A}$	T _J = 125°C		0.8		V
Reverse Recovery Time	t _{RR}	$V_{GS} = 0 \text{ V, dIS/dt} = 100 \text{ A/}\mu\text{s,}$ $I_{S} = 30 \text{ A}$			22.2		ns
Charge Time	t _a				12.5		
Discharge Time	t _b				9.7		
Reverse Recovery Charge	Q_{RR}				10.8		nC
PACKAGE PARASITIC VALUES							
Source Inductance	L _S				0.93		nΗ
Drain Inductance	L _D	T _A = 25°C 0.005 1.84 3.3			0.005		nΗ
Gate Inductance	L _G					nH	
Gate Resistance	R _G					Ω	

5. Pulse Test: pulse width \leq 300 μ s, duty cycle \leq 2%.

^{6.} Switching characteristics are independent of operating junction temperatures.

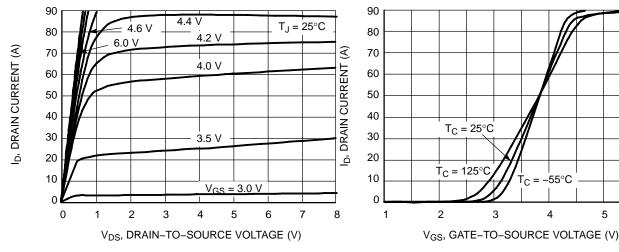


Figure 1. On-Region Characteristics

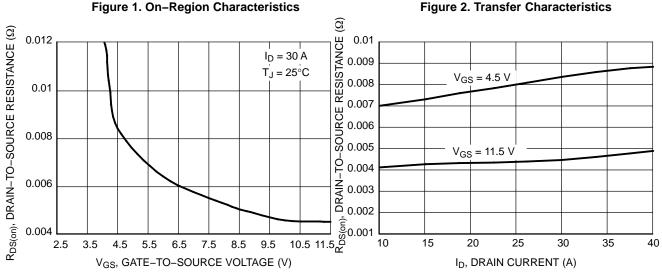
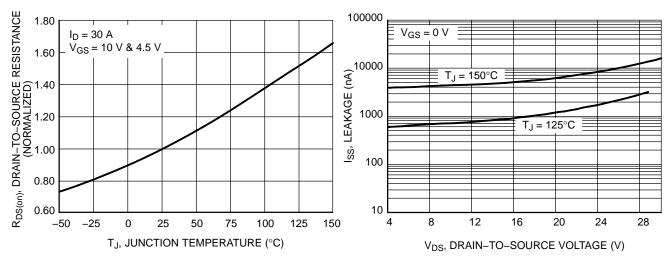


Figure 3. On-Resistance versus Gate-to-Source Voltage

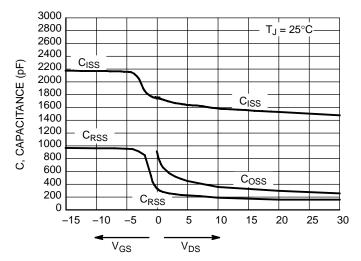
Figure 4. On-Resistance versus Drain Current and Temperature

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www.DataSheet4U.corFigure 5. On–Resistance Variation with Temperature

Figure 6. Drain-to-Source Leakage Current versus Voltage



GATE-TO-SOURCE OR DRAIN-TO-SOURCE VOLTAGE (V)

Figure 7. Capacitance Variation

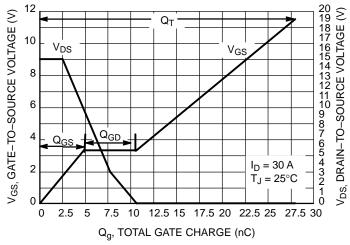


Figure 8. Gate-to-Source and Drain-to-Source Voltage vs. Total Gate Charge

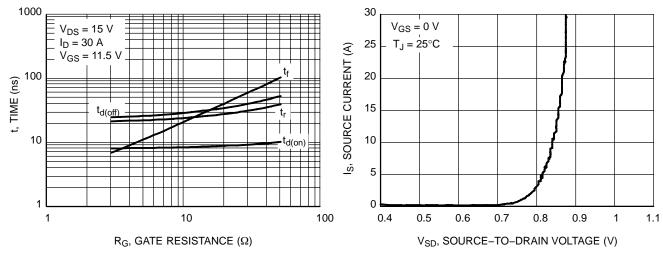


Figure 9. Resistive Switching Time www.DataSheet4U.conVariation versus Gate Resistance

Figure 10. Diode Forward Voltage versus Current

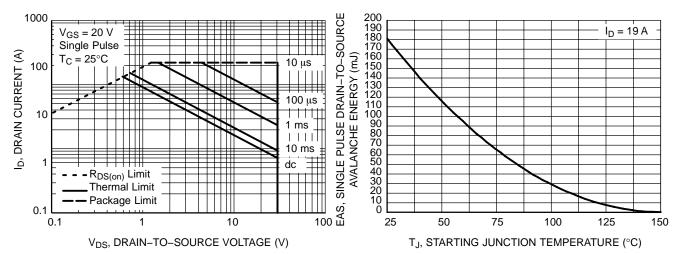
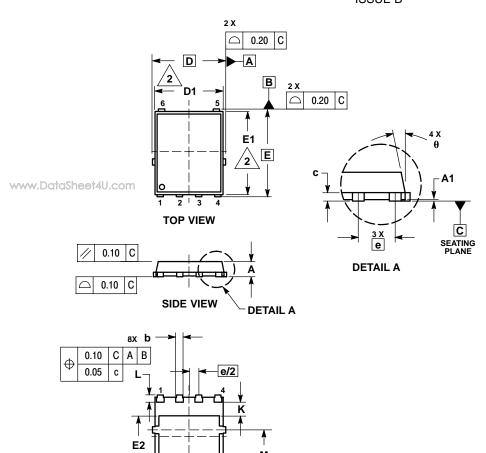


Figure 11. Maximum Rated Forward Biased Safe Operating Area

Figure 12. Maximum Avalanche Energy versus Starting Junction Temperature

PACKAGE DIMENSIONS

SO-8 FLAT LEAD (DFN6) CASE 488AA-01 ISSUE B



NOTES:

- DIMENSIONING AND TOLERANCING PER ASME Y14.5M, 1994. CONTROLLING DIMENSION: MILLIMETER.
- DIMENSION D1 AND E1 DO NOT INCLUDE MOLD FLASH PROTRUSIONS OR GATE

	MILLIMETERS					
DIM	MIN	NOM	MAX			
Α	0.90	0.99	1.20			
A1	0.00		0.05			
b	0.33	0.41	0.51			
C	0.23	0.28	0.33			
D		5.15 BSC	;			
D1	4.50	4.90	5.10			
D2	3.50		4.22			
Е	6.15 BSC					
E1	5.50	5.80	6.10			
E2	3.45		4.30			
е	1.27 BSC					
G	0.51	0.61	0.71			
K	0.51					
L	0.51	0.61	0.71			
L1	0.05	0.17	0.20			
М	3.00	3.40	3.80			
θ	0 °	-	12 °			

STYLE 1:

PIN 1. SOURCE 2. SOURCE

- 3. SOURCE 4. GATE
- 5. DRAIN 6. DRAIN

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